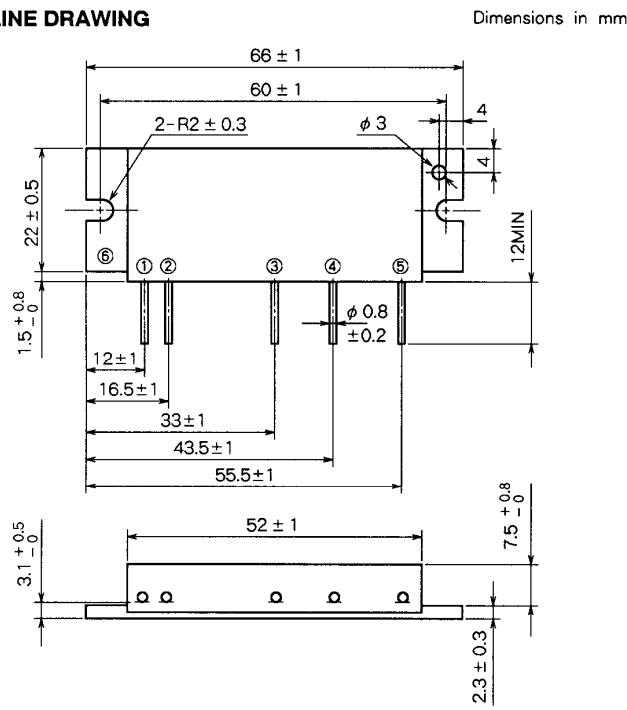
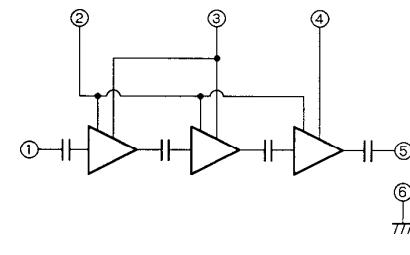


**OUTLINE DRAWING****BLOCK DIAGRAM**

## PIN :

- ①Pin : RF INPUT
- ②V<sub>BB</sub> : BASE BIAS SUPPLY
- ③V<sub>CC1</sub> : 1st. DC SUPPLY
- ④V<sub>CC2</sub> : 2nd. DC SUPPLY
- ⑤P<sub>O</sub> : RF OUTPUT
- ⑥GND : FIN

**ABSOLUTE MAXIMUM RATINGS** ( $T_c = 25^\circ\text{C}$  unless otherwise noted)

Symbol	Parameter	Conditions	Ratings	Unit
V <sub>CC</sub>	Supply voltage		17	V
V <sub>BB</sub>	Base bias		10	V
I <sub>CC</sub>	Total current		10	A
P <sub>IN(max)</sub>	Input power	$Z_g = Z_L = 50 \Omega$	0.5	W
P <sub>O(max)</sub>	Output power	$Z_g = Z_L = 50 \Omega$	40	W
T <sub>C(OP)</sub>	Operation case temperature		-30 to 110	°C
T <sub>STG</sub>	Storage temperature		-40 to 110	°C

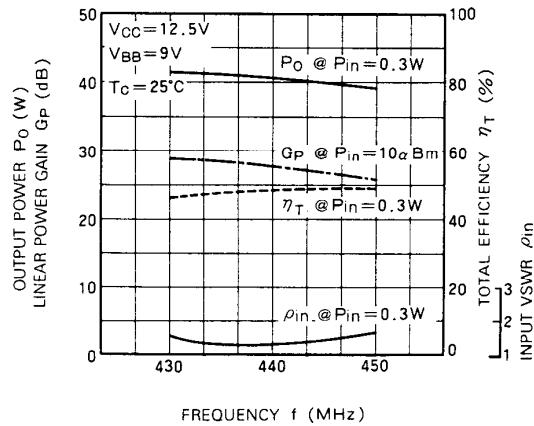
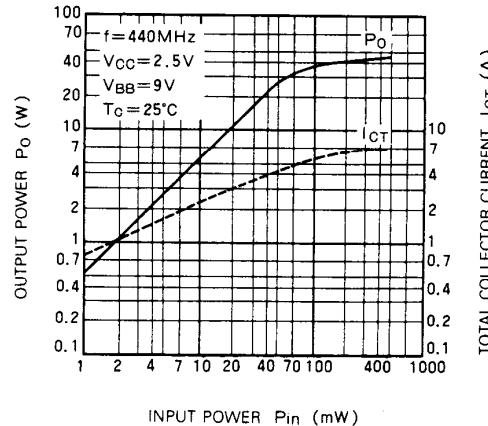
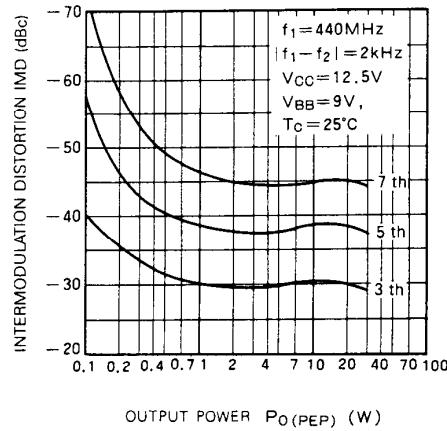
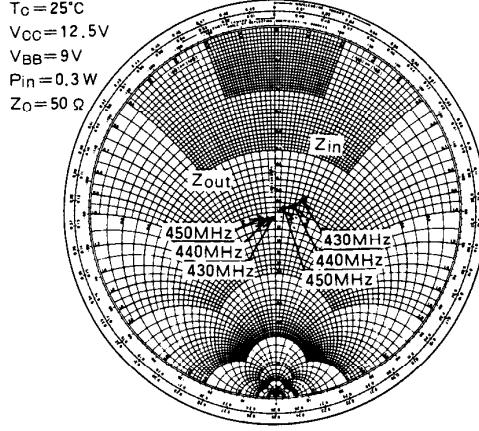
Note. Above parameters are guaranteed independently.

**ELECTRICAL CHARACTERISTICS** ( $T_c = 25^\circ\text{C}$  unless otherwise noted)

Symbol	Parameter	Test conditions	Limits		Unit
			Min	Max	
f	Frequency range		430	450	MHz
P <sub>O</sub>	Output power	$P_{in} = 0.3\text{W}$	33		W
$\eta_T$	Total efficiency	$V_{CC} = 12.5\text{V}$	40		%
2f <sub>o</sub>	2nd. harmonic	$V_{BB} = 9\text{V}$		-30	dBc
3f <sub>o</sub>	3rd. harmonic	$Z_g = Z_L = 50 \Omega$		-30	dBc
$\rho_{in}$	Input VSWR			2.5	-
-	Load VSWR tolerance	$V_{CC} = 15.2\text{V}, V_{BB} = 9\text{V}$ $P_{in} = 30\text{W}$ ( $P_{in}$ : controlled) Load VSWR = 8.8 : 1 (All phase), $Z_g = 50 \Omega$	No degradation or destroy		-

Note. Above parameters, ratings, limits and conditions are subject to change.

## TYPICAL PERFORMANCE DATA

OUTPUT POWER, LINEAR POWER GAIN,  
TOTAL EFFICIENCY, INPUT VSWR  
VS. FREQUENCYOUTPUT POWER, TOTAL COLLECTOR  
CURRENT, VS. INPUT POWERINTERMODULATION DISTORTION  
VS. OUTPUT POWERINPUT IMPEDANCE, OUTPUT IMPEDANCE  
VS. FREQUENCY

## DESIGN CONSIDERATION OF HEAT RADIATION.

Please refer to following consideration when designing heat sink.

### 1. Junction temperature of incorporated transistors at standard operation.

- (1) Thermal resistance between junction and package of incorporated transistors.

#### a) First stage transistor

$$R_{th(j-c)1} = 12^\circ\text{C/W (Typ.)}$$

#### b) Second stage transistor

$$R_{th(j-c)2} = 4^\circ\text{C/W (Typ.)}$$

#### c) Final stage transistor

$$R_{th(j-c)3} = 1.75^\circ\text{C/W (Typ.)}$$

- (2) Junction temperature of incorporated transistors at standard operation.

#### • Conditions for standard operation.

$P_o = 30\text{W}$ ,  $V_{CC} = 12.5\text{V}$ ,  $P_{in} = 0.3\text{W}$ ,  $\eta_T = 40\%$  (minimum rating),  $P_{o1}^{(Note 1)} = 2\text{W}$ ,  $P_{o2}^{(2)} = 8\text{W}$ ,  $I_T = 6\text{A}$  ( $I_{T1}^{(3)} = 0.35\text{A}$ ,  $I_{T2}^{(4)} = 1.32\text{A}$ ,  $I_{T3}^{(5)} = 4.33\text{A}$ )

Note 1: Output power of the first stage transistor

Note 2: Output power of the second stage transistor

Note 3: Circuit current of the first stage transistor

Note 4: Circuit current of the second stage transistor

Note 5: Circuit current of the final stage transistor

#### • Junction temperature of the first stage transistor

$$\begin{aligned} T_{j1} &\approx (V_{CC} \times I_{T1} - P_{o1} + P_{in}) \times R_{th(j-c)1} + T_c^{(6)} \\ &= (12.5 \times 0.35 - 2 + 0.3) \times 12 + T_c \\ &= 32 + T_c (\text{ }^\circ\text{C}) \end{aligned}$$

Note 6: Package temperature of device

#### • Junction temperature of the second stage transistor

$$\begin{aligned} T_{j2} &= (V_{CC} \times I_{T2} - P_{o2} + P_{o1}) \times R_{th(j-c)2} + T_c \\ &= (12.5 \times 1.32 - 8 + 2) \times 4 + T_c \\ &= 42 + T_c (\text{ }^\circ\text{C}) \end{aligned}$$

#### • Junction temperature of the final stage transistor

$$\begin{aligned} T_{j3} &= (V_{CC} \times I_{T3} - P_o + P_{o2}) \times R_{th(j-c)3} + T_c \\ &= (12.5 \times 4.33 - 30 + 8) \times 1.75 + T_c \\ &= 56 + T_c (\text{ }^\circ\text{C}) \end{aligned}$$

## 2. Heat sink design

In thermal design of heat sink, try to keep the package temperature at the upper limit of the operating ambient temperature (normally  $T_a = 60^\circ\text{C}$ ) and at the output power of 30W below  $90^\circ\text{C}$ .

The thermal resistance  $R_{th(c-a)}^{(7)}$  of the heat sink to realize this:

$$\begin{aligned} R_{th(c-a)} &= \frac{T_c - T_a}{(P_o/\eta_T) - P_o + P_{in}} = \frac{90 - 60}{(30/0.4) - 30 + 0.3} \\ &= 0.66 (\text{ }^\circ\text{C/W}) \end{aligned}$$

Note 7: Inclusive of the contact thermal resistance between device and heat sink.

Mounting the heat sink of the above thermal resistance on the device,

$$\begin{aligned} T_{j1} &= 122^\circ\text{C}, T_{j2} = 132^\circ\text{C}, T_{j3} = 146^\circ\text{C} \text{ at } T_a = 60^\circ\text{C}, \\ T_c &= 90^\circ\text{C}. \end{aligned}$$

In the annual average of ambient temperature is  $30^\circ\text{C}$ ,

$$T_{j1} = 92^\circ\text{C}, T_{j2} = 102^\circ\text{C}, T_{j3} = 116^\circ\text{C}.$$

As the maximum junction temperature of these incorporated transistors  $T_{jmax}$  are  $175^\circ\text{C}$ , application under fully derated condition is ensured.